Search Notes		

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/867,570	WEI ET AL.	
	Examiner	Art Unit	
٠	lon M. Lockard	1647	

SEARCHED			
Class	Subclass	Date	Examiner
435	69.1	1/10/2005	JML
	252.3	1/10/2005	JML
	320.1	1/10/2005	JML
	325	1/10/2005	JML
530	350	1/10/2005	JML
536	23.5	1/10/2005	JML
	24.31	1/10/2005	JML.
NONE		8/29/2005	JML

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Stic Search of Commercial and Patent Databases: See Attached Search Report	11/1/2004	JML
Stic Search of Commercial and Patent Databases: See Attached Search Report	12/3/2004	JML
PALM Inventor Name Search	1/10/2005	JML
East Search: See Attached Search Report	1/10/2005	JML
East Search (USPAT, US-PGPUB, EPO, DERWENT): Inventor's Name Search. See Attached Search History.	8/29/2005	JML
PALM: Inventor's Name Search.	8/29/2005	JML
STN (MEDLINE, SCISEARCH, EMBASE, BIOSIS): Text and Inventor's Name Search. See Attached Search History.	8/29/2005	JML